## Search Notes



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Applicant(s)/Patent Under Reexamination LEE ET AL.

LEEEIA

Examiner

Art Unit

MARCOS BATISTA

## SEARCHED

Class	Subclass	Date	Examiner
455	466	2/14/2008	mb
455	95	2/14/2008	mb

## **SEARCH NOTES**

Search Notes	Date	Examiner
Consulted with Steve D'Agosta	2/19/2008	mb
Consulted with TA - Yogesh Aggarwal	2/14/2008	mb
Consulted with Lun-YI Lao	2/19/2008	mb
East Search	2/14/2008	mb
Inventor's Name Seach	2/14/2008	mb
East Search	12/5/2008	mb
Consulted with Rafael Perez Gutierrez	12/4/2008	mb

	INTERFERENCE SEARCH		
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